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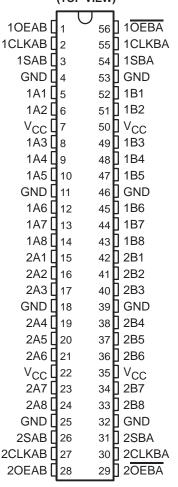
- Members of the Texas Instruments
   Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- Independent Registers and Enables for A and B Buses
- Multiplexed Real-Time and Stored Data
- Flow-Through Architecture Optimizes
   PCB Layout
- Distributed V<sub>CC</sub> and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPIC<sup>™</sup> (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Spacings

### description

The 'ACT16652 are 16-bit bus transceivers consisting of D-type flip-flops and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. The devices can be used as two 8-bit transceivers or one 16-bit transceiver.

Complementary output-enable (OEAB and OEBA) inputs are provided to control the transceiver functions. Select-control (SAB and SBA) inputs are provided to select whether real-time or stored data is transferred. A low input level selects real-time data, and a high input level selects stored data. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the 'ACT16652.

#### 54ACT16652... WD PACAGE 74ACT16652... DL PACKAGE (TOP VIEW)





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## 54ACT16652, 74ACT16652 16-BIT TRANSCEIVERS AND REGISTERS WITH 3-STATE OUTPUTS

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### description (continued)

Data on the A or B bus, or both, can be stored in the internal D flip-flops by low-to-high transitions at the appropriate clock (CLKAB or CLKBA) inputs, regardless of the levels on the select-control or output-enable inputs. When SAB and SBA are in the real-time transfer mode, it is also possible to store data without using the internal D-type flip-flops by simultaneously enabling OEAB and OEBA. In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set of bus lines remains at its last state.

The 74ACT16652 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The 54ACT16652 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The 74ACT16652 is characterized for operation from  $-40^{\circ}$ C to 85°C.

#### **FUNCTION TABLE**

· · · · · · · · · · · · · · · · · · ·											
		INP	UTS			DATA	A 1/0†	ODED ATION OD EUNOTION			
OEAB	OEBA	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION			
L	Н	L	L	Х	Х	Input	Input	Isolation			
L	Н	$\uparrow$	$\uparrow$	X	Χ	Input	Input	Store A and B data			
Х	Н	1	L	Х	Х	Input	Unspecified <sup>‡</sup>	Store A, hold B			
Н	Н	$\uparrow$	$\uparrow$	χ‡	Χ	Input	Output	Store A in both registers			
L	Х	L	$\uparrow$	Х	Х	Unspecified <sup>‡</sup>	Input	Hold A, store B			
L	L	$\uparrow$	$\uparrow$	X	<b>X</b> ‡	Output	Input	Store B in both registers			
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus			
L	L	X	L	X	Н	Output	Input	Stored B data to A bus			
Н	Н	Х	Х	L	Х	Input	Output	Real-time A data to B bus			
Н	Н	L	Χ	Н	Χ	Input	Output	Stored A data to B bus			
Н	L	L	L	Н	Н	Output	Output	Stored A data to B bus and stored B data to A bus			

<sup>†</sup> The data-output functions may be enabled or disabled by a variety of level combinations at OEAB or OEBA. Data-input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.



<sup>‡</sup> Select control = L; clocks can occur simultaneously.

Select control = H; clocks must be staggered to load both registers.

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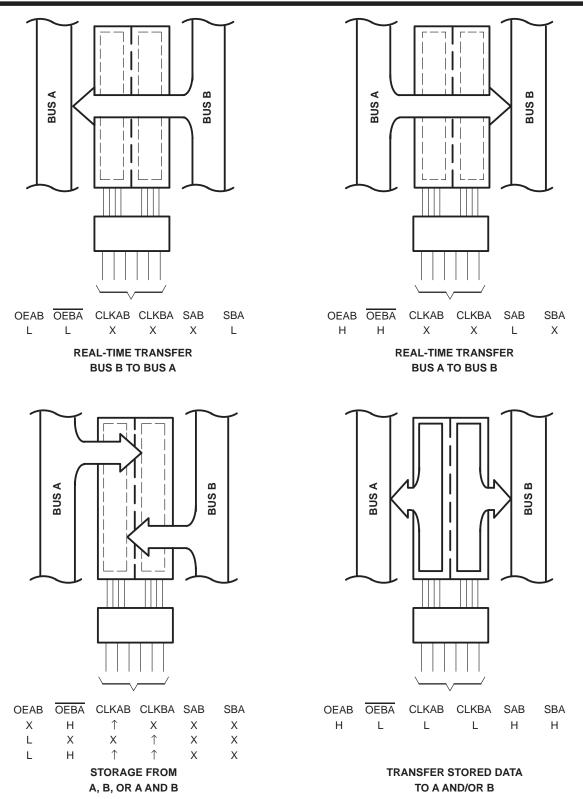
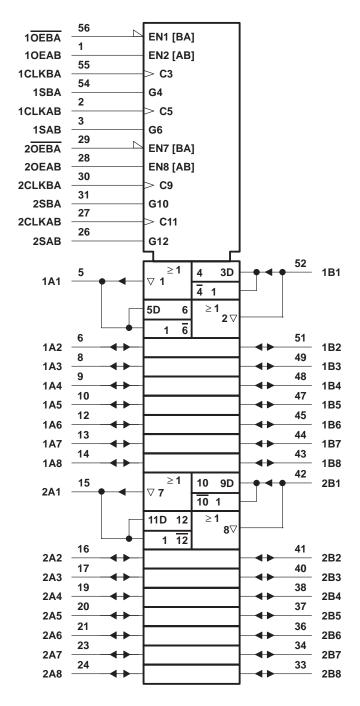


Figure 1. Bus-Management Functions



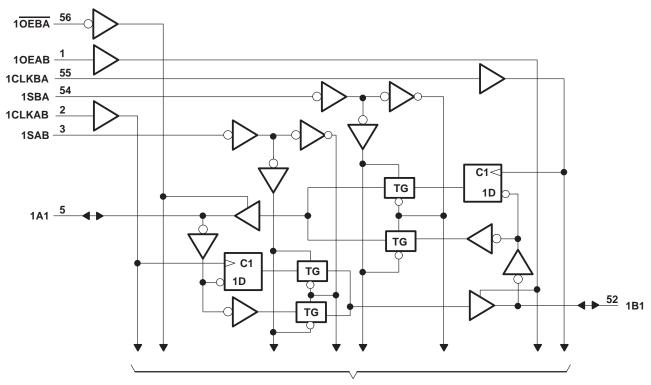
## logic symbol†



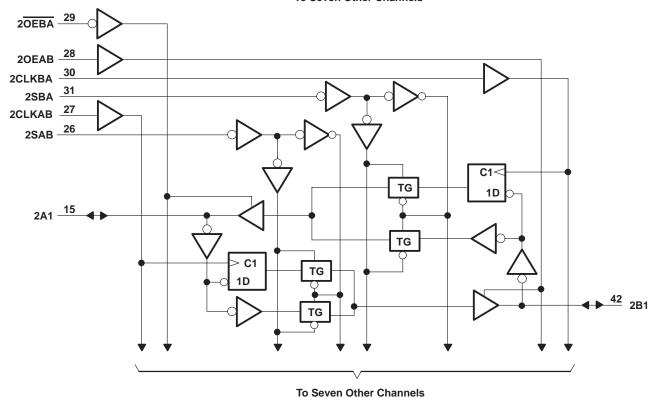
<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



## logic diagram (positive logic)



To Seven Other Channels



## 54ACT16652, 74ACT16652 16-BIT TRANSCEIVERS AND REGISTERS WITH 3-STATE OUTPUTS

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)—0	$.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V <sub>O</sub> (see Note 1)0	$.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±50 mA
Continuous current through V <sub>CC</sub> or GND	±400 mA
Maximum package power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2): DL package	1.4 W
Storage temperature range, T <sub>stq</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions (see Note 3)

		54ACT16652			74.	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		7	2			V
VIL	Low-level input voltage		Š	0.8			0.8	V
٧ <sub>I</sub>	Input voltage	0	70/2	VCC	0		VCC	V
Vo	Output voltage	0	7	VCC	0		VCC	V
loh	High-level output current		3	-24			-24	mA
lOL	Low-level output current	20	5	24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>2.</sup> The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	TA = $25^{\circ}$ C  TONDITIONS  VCC				54ACT	16652	74ACT16652		UNIT	
		TEST CONDITIONS	100	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT	
		Jour 50 11A	4.5 V	4.4			4.4		4.4			
		I <sub>OH</sub> = -50 μA	5.5 V	5.4			5.4		5.4			
Voн		I <sub>OH</sub> = -24 mA	4.5 V	3.94			3.8		3.8		V	
		10H = -24 IIIA	5.5 V	4.94			4.8		4.8			
		I <sub>OH</sub> = -75 mA <sup>†</sup>	5.5 V				3.85	N.	3.85			
		I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	V	
		ΙΟΣ = 30 μΑ	5.5 V			0.1		0.1		0.1		
VOL		10 24 mA	4.5 V			0.36	, C	0.44		0.44		
		I <sub>OL</sub> = 24 mA	5.5 V			0.36	20	0.44		0.44		
		I <sub>OL</sub> = 75 mA <sup>†</sup>	5.5 V				20	1.65		1.65		
П	Control inputs	$V_I = V_{CC}$ or GND	5.5 V			±0.1	y	±1		±1	μΑ	
loz <sup>‡</sup>	A or B ports	$V_O = V_{CC}$ or GND	5.5 V			±0.5		±5		±5	μΑ	
Icc		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80		80	μΑ	
ΔICC§		One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND	5.5 V			0.9		1		1	mA	
Ci	Control inputs	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4						pF	
Cio	A or B ports	$V_O = V_{CC}$ or GND	5 V		12						pF	

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

			T <sub>A</sub> = 25°C		54ACT16652		74ACT16652	
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
fclock	Clock frequency	0	90	0	90	0	90	MHz
t <sub>W</sub>	Pulse duration, CLKAB or CLKBA high or low	5.5		5.5		5.5		ns
t <sub>su</sub>	Setup time, A before CLKAB↑ or B before CLKBA↑	4.5		4.5		4.5		ns
t <sub>h</sub>	Hold time, A after CLKAB↑ or B after CLKBA↑	1		1		1		ns

 $<sup>\</sup>mbox{\ensuremath{\mbox{\,^{\begin{tabular}{c}}}}}\mbox{\ensuremath{\mbox{\,^{\begin{tabular}{c}}}}}\mbox{\ensuremath{\mbox{\,^{\begin{tabular}{c}}}}\mbox{\ensuremath{\mbox{\,^{\begin{tabular}{c}}}}}\mbox{\ensuremath{\mbox{\,^{\begin{ta$ 

<sup>§</sup> This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

## 54ACT16652, 74ACT16652 16-BIT TRANSCEIVERS AND REGISTERS WITH 3-STATE OUTPUTS

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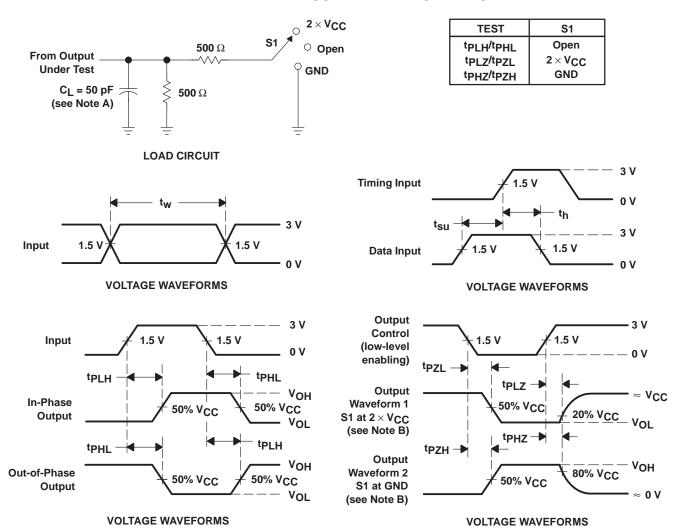
# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	то	T,	T <sub>A</sub> = 25°C			16652	74ACT	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT
f <sub>max</sub>			90			90		90		MHz
<sup>t</sup> PLH	A or B	B or A	3.7	7.2	9.4	3.7	10.5	3.7	10.5	ns
<sup>t</sup> PHL	A or B	BOIA	3	8.1	10.5	3	11.6	3	11.6	113
t <sub>PLH</sub>	CLKBA or CLKAB	A or B	4.5	8.7	11.2	4.5	12.3	4.5	12.3	ns
<sup>t</sup> PHL	CLNBA OF CLNAB	AOIB	4.9	8.9	11.3	4.9	12.3	4.9	12.3	IIS
t <sub>PLH</sub>	SBA or SAB	A or B	4.9	10.4	14.1	4.9	16	4.9	16	ns
<sup>t</sup> PHL	(with A or B high)	AUID	4.6	8.4	10.6	4.6	11.7	4.6	11.7	115
<sup>t</sup> PLH	SBA or SAB	A or B	3.9	7.8	10	3.9	11.2	3.9	11.2	ns
<sup>t</sup> PHL	(with A or B low)	AUIB	5.6	12.3	14.9	5.6	16.9	5.6	16.9	115
<sup>t</sup> PZH	<del>OEBA</del>	А	3	8.1	10.5	3	11.7	3	11.7	ns
t <sub>PZL</sub>	OEBA		3.9	9.4	12	3.9	13.4	3.9	13.4	
<sup>t</sup> PHZ	OED4	А	5.3	7.4	8.9	5.3	9.5	5.3	9.5	ns
t <sub>PLZ</sub>	OEBA	A	4.8	6.8	8.6	4.8	9.2	4.8	9.2	115
<sup>t</sup> PZH	OEAB	В	4.1	7.7	9.8	4.1	10.8	4.1	10.8	ns
t <sub>PZL</sub>	OEAB	VEAD   B	5	9	11	5	12.4	5	12.4	115
<sup>t</sup> PHZ	OEAB	В	4.4	8.1	10.1	4.4	10.5	4.4	10.5	ns
t <sub>PLZ</sub>	OLAB	, d	4.3	7.7	9.7	4.3	9.9	4.3	9.9	115

# operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CO	TYP	UNIT		
C <sub>pd</sub>	Dower discipation canacitance per transcriver	Outputs enabled	C 50 pE	f = 1 MHz	57	, r
	Power dissipation capacitance per transceiver	Outputs disabled	C <sub>L</sub> = 50 pF,	I = I IVIIIZ	13	рF

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f = 3 \text{ ns}$ ,  $t_f = 3 \text{ ns}$ .
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms

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